



FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS ANNOUNCES FOX-1™ FULL WAFER TEST SYSTEM

Fremont, CA (June 6, 2005) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced the availability of the FOX-1 full wafer contact test and burn-in system. The FOX-1 test system is the third member of the FOX family of full wafer contact systems and is focused on testing an entire wafer of devices with a single touchdown or for short-duration burn-in and test. The other members of Aehr Test’s FOX family of products are focused on long-duration full wafer burn-in and test of products such as DRAMs or VCSELs (laser diodes).

“The FOX-1 system represents the convergence of three major technologies,” said Steve Steps, senior director of wafer-level burn-in and test. “By combining our years of experience in full wafer contact technology, massively parallel test and Design For Test (DFT), we have created a product that can cost-effectively test an entire wafer with a single touchdown. This enables very significant reductions in test time and cost-per-tested-die.”

“Our key customers are looking for innovative technology to reduce the escalating cost of testing,” said Greg Perkins, vice president of sales and service of Aehr Test. “We hope to see a high interest level in this new system from semiconductor manufacturers worldwide.”

“We saw the potential for full wafer test several years ago,” said Rhea Posedel, chairman and chief executive officer of Aehr Test. “The FOX-1 full wafer test system represents a natural progression for our existing industry leadership position in full wafer burn-in and massively parallel test. We are excited about sales potential for the FOX-1 system as it moves the company into a new market for massively parallel testing.”

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-

in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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